Functional Statistics: Outliers Detection and Quality Control

Guest Editor:

Prof. Dr. Javier Martínez Torres

Escuela Superior de Ingeniería y Tecnología. Universidad Internacional de La Rioja, 26006 Logroño, Spain

Deadline for manuscript submissions:
closed (31 October 2020)

Message from the Guest Editor

Dear Colleagues,

At present, a large amount of data can be approached from the functional prism and in a multitude of fields such as engineering, medicine, etc. An example of this, which is very important to the engineering (mechanical, electronic, environmental, etc.) field, is quality control, which is based on the classical Schewart methodology or WECO rules.

However, while application is important, a comparison between methods, and the design and construction of a new model, univariable or multivariable, based on depth, non-parametric, etc., is also important. Thus, in this Special Issue, different articles are collected with new models of detection of functional outliers, or applications thereof, on different areas of quality control and process capability control.

Prof. Dr. Javier Martínez Torres
Guest Editor

Special Issue

Editor-in-Chief

Prof. Dr. Francisco Chiclana
School of Computer Science and Informatics, De Montfort University, The Gateway, Leicester LE1 9BH, UK

Message from the Editor-in-Chief

The journal *Mathematics* publishes high-quality, refereed papers that treat both pure and applied mathematics. The journal highlights articles devoted to the mathematical treatment of questions arising in physics, chemistry, biology, statistics, finance, computer science, engineering and sociology, particularly those that stress analytical/algebraic aspects and novel problems and their solutions. One of the missions of the journal is to serve mathematicians and scientists through the prompt publication of significant advances in any branch of science and technology, and to provide a forum for the discussion of new scientific developments.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.
High Visibility: indexed within Scopus, SCIE (Web of Science), RePEc, and other databases.
Journal Rank: JCR - Q1 (*Mathematics*) / CiteScore - Q1 (*General Mathematics*)

Contact Us